

Volume 26, Number 5 October 2020

Microscopy AND Microanalysis



CAMBRIDGE
UNIVERSITY PRESS

ISSN 1431-9276

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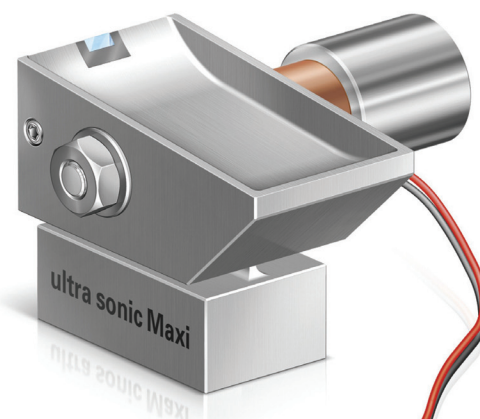
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The ultra Maxi is similar to our ultra 35° 4.0 mm but with a larger boat.
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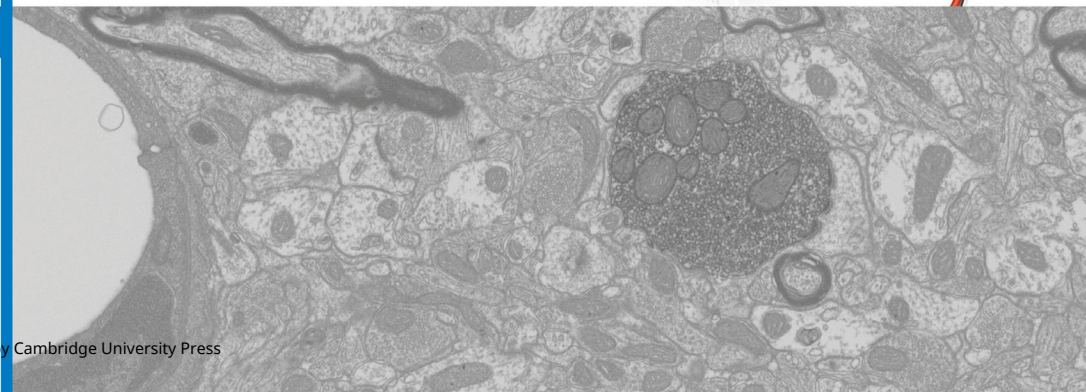


NEW ultra sonic Maxi

The ultra sonic Maxi is a new wider ultra sonic knife specifically for compression-free serial sectioning in biological applications. The knife comes in 3.0mm and 4.0mm sizes with 35° angle.



Biocytin-labeled giant bouton from the auditory cortex of a Mongolian gerbil acquired with a scanning electron microscope. Saldeitis et al., 2019 Eur. J. Neurosci. Vol.50-9:3445-3453.



for more information, please visit our website at...

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Microscopy AND Microanalysis

An International Journal for the Biological and Physical Sciences

THE OFFICIAL JOURNAL OF

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PUBLISHED IN AFFILIATION WITH

ROYAL MICROSCOPICAL SOCIETY
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Microscopy and Microanalysis is published bimonthly in February, April, June, August, October, and December by Cambridge University Press (1 Liberty Plaza, New York, NY 10006). Three supplements (*Meeting Guide*, *Program Guide*, and *Proceedings*) are published in June and August.

Society Rates: Members of the Microscopy Society of America should contact the MSA Business Office for all subscription inquiries: Microscopy Society of America, 11130 Sunrise Valley Dr, Suite 350, Reston, VA 20191, Tel.: (703) 234-4115, Email: associationmanagement@microscopy.org, URL: www.microscopy.org. Members of other affiliated societies should contact their respective society business offices for all subscription inquiries.

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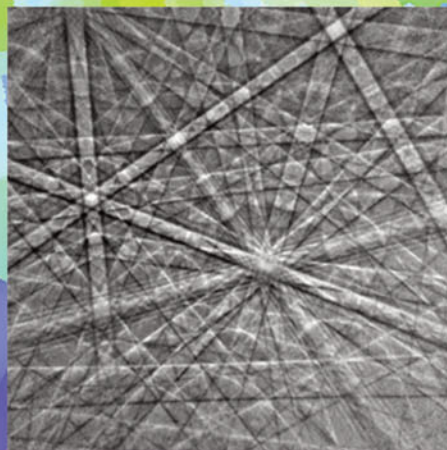
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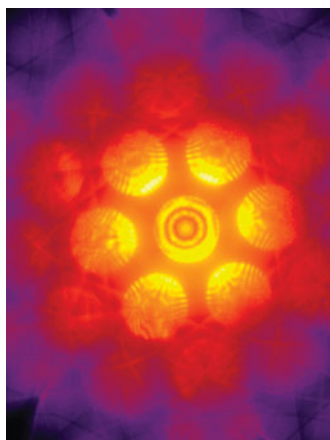
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An International Journal for the Biological and Physical Sciences

Volume 26, Number 5
October 2020



On the Cover: A finely sampled Si $\langle 111 \rangle$ CBED pattern after stitching together 128×128 pixel sub-patterns captured with a Electron Microscopy Pixel Array Detector. See “Expanding the Dimensions of a Small, Two-Dimensional Diffraction Detector” by Chen et. al.

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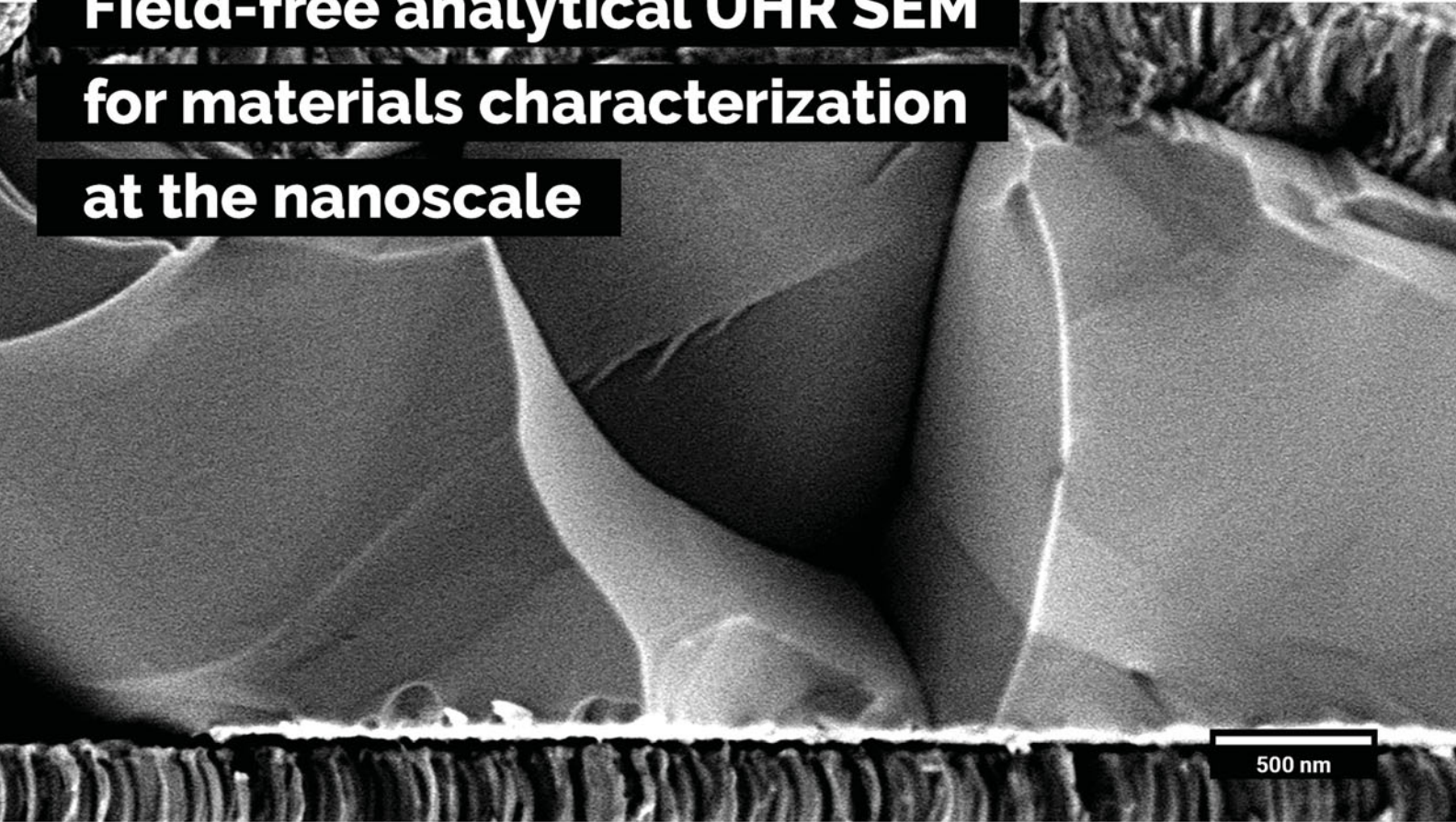
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Field-free analytical UHR SEM for materials characterization at the nanoscale



500 nm

Fracture of solar cell, imaged at 2 keV, E-T detector
Sample courtesy of Center for Solar Energy and Hydrogen Research Baden-Württemberg, Stuttgart

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